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Application of

OCT 1 5 2002

Applicants

: David R. Hembree et al.

TECHNOLOGY CENTER 2800

Serial No.

: 09/510,828

Filed

: February 23, 2000

Title

: A SPRING ELEMENT FOR USE IN AN APPARATUS FOR ATTACHING

TO A SEMICONDUCTOR AND A METHOD OF MAKING

Docket No.

: MIO0020VA (97-0198.02)

Examiner

: J. Mitchell

Art Unit

: 2822

Confirmation: 4071

CERTIFICATE OF FACSIMALE TRANSMISSION

Assistant Commissioner for Patents

Washington, D.C. 20231

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724) on Oxtober 15, 2002.

Sir:

AMENDMENT

This paper is being filed in response to the Office Action dated July 31, 2002 in the identified application, having a reply due date of October 31, 2002. Reconsideration is respectfully requested in light of the remarks below.

IN THE CLAIMS

The entire set of presently pending claims is reproduced below for the convenience of the Examiner. Amended claims are indicated as such in the parenthetical following the claim number. Further, enclosed herewith is a separate paper entitled "Version With Markings To Show Changes Made" which corresponds to the amendments to the claims

made herein. 00000007 09510828 DO2 TBELL1

01 FC:1202 02 FC:1201

Please amend @ams 29, 54, 68 and 73.

4

Please also add new claims 74-88.



Patents, Trademarks and Related Matters Killworth, Gottman, Hagan & Schaeff, L.L.P.

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FEE TRANSMITTAL for FY 2002 Palont fees are subject to annual revision.

Applicant claims small entity status. See 37 CFR 1.27

210.00 **TOTAL AMOUNT OF PAYMENT**

Complete if Known				
Application Number	09/510,828			
Filing Date	February 23, 2000			
First Named Inventor	David R. Hembree			
Examiner Name	J. Mitchell			
Group Art Unit	2822			
Attorney Docket No.	MIO 0020 VA			

METHOD OF PAYMENT (check all that apply)			FEE CALCULATION (continued)							
Check X Credit card Money Other None			3. ADDITIONAL FEES							
Order —			Large Entity Small Entity							
Deposit /	ACCOUNT:			Fra Code	Fee (\$)	Fee	Foe 9 (\$)	Fee Description	Fee Paid	
Account Number				105	130	205	65	Surcharge - late filling fee or wath		
Deposit Account Name				127	50	227	25	Surcharge - late provisional filing fee or cover sheet		
The Commissi	ioner is authoriz	zed to; (chock all that a	apply)	139	130	139	130	Non-English specification		
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Charge any additional fee(s) during the pendency of this application			112	920*	112		Requesting publication of SIR prior to			
Charge fee(s) indicated below, except for the filing fee							Examiner action			
to the above identified deposit account.			113	1,840"	113	1,840*	Requesting publication of SIR after Examiner action			
FEE CALCULATION			115	110	215	55	Extension for reply within first month			
1. BASIC FI				116	400	216	200	Extension for reply within second month		
Large Entity	Fee Fee	Fee Description		117	920	217	460	Extension for reply within third month		
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101 740	201 370	Utility filing fee			1,960	l	980	Extension for reply within fifth month		
108 330	206 165	Design filling fee		119	320	219	160	Notice of Appeal		
107 510	207 255	Plant filling fee	\\	130	320	220	160	Filing a brief in support of an appeal		
108 74D	208 370	Reissue filing fee		121	280	221	140	Request for oral hearing		
114 160	214 80	Provisional filing fee		Ď.	1,510	1	1,510	Petition to institute a public use proceeding		
SUBTOTAL (1) (\$) 0.00			140	110	240	55	Patition to revive - unavoidable			
2. EXTRA CLAIM FEES FOR UTILITY AND REISSUE			D REISSUE	141	1,280	241	640	Patition to revive - unintentional		
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Total Claims	59 -20**			143	460	243	230	Design Issue fee		
Independent Claims	8 - 3**	= 0 × 84.0	0.00	144	520	244	310	Plant issue fee		
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				123	50	123	50	Processing fee under 37 CFR 1.17(q)		
Large Entity		Par Buralasi -		125	180	126	180	Submission of Information Disclosure Stmt		
Fee Fee Code (\$)	Fee Fcc Code (\$)	Fee Description		581	40	581	40	Recording each patent assignment per		
103 18	203 9	Claims in excess of 2	20	A				property (times number of properties)		
102 84	202 42	Independent claims li	n excess of 3	146	740	246	370	Filing a submission after final rejection (37 CFR § 1.129(a))		
104 280	204 140	Multiple dependent o	talm, if not paid	149	740	249	370	For each additional invention to be		
109 84	209 42	bneqobni eussieR ** netra innigiro revo						examined (37 CFR § 1,129(b))		
110 18 210 9 ** Reissub claims in excess of 20		179	740	279	370	Request for Continued Examination (RCE)				
and over original patent			169	900	169		Request for expedited examination of a design application			
SUBTOTAL (2) (\$) 210.00			Other fan (aprocify)							
**or number previously paid, if greater, For Reissues spo above				Rec	luged b	у Баз	ic Fllin	S Fee Paid SUBTOTAL (3)	0.00	

SUBMITTED BY		7			Complete (li	epplicable)
Name (PrintlType)	Thomas B.	 //	Registration No. (AllerneylAgent)	46,867	Telaphone	(937) 223-2050
Signature	pho	00	2		Date	October 15, 2002

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29. (Amended) An apparatus for attaching to a plurality of contacts of a semiconductor, said apparatus comprising:

an interconnect structure comprising a plurality of conductors patterned to match corresponding ones of said plurality of contacts of said semiconductor; and

an attachment device comprising a spring element including an elastic member comprised of a first elastomeric material and a conductive member, said attachment device arranged to press said semiconductor between said spring element and said interconnect structure to provide an electrical connection between said plurality of conductors and said corresponding ones of said plurality of contacts, said attachment device.

- The apparatus of claim 29, wherein said conductive member comprises a plurality 30. of conductive particles.
- The apparatus of claim 29, wherein said plurality of conductive particles are 31. interspersed within said elastomeric member.
- The apparatus of claim 29, wherein said conductive member is comprised of 36. conductive material selected from the group consisting of gold, aluminum, nickel, silver stainless steel, and alloys thereof
- The apparatus of claim 2\$\, wherein said semiconductor is electrically biased 37. through said spring element.
- The apparatus of claim 29, wherein said semiconductor comprises a semiconductor 38. die.

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- The apparatus of claim 29, wherein said semiconductor comprises a semiconductor 39. die formed within a semiconductor package.
- The apparatus of claim 39, wherein said semiconductor package comprises a 40. package selected from the group consisting of a chip-scale package, a ball grid array, a chip-on-board, a direct chip attach, and a flip-chip.
- 44. An apparatus for attaching to a plurality of contacts of a semiconductor, said apparatus comprising:

an interconnect structure comprising a plurality of conductors patterned to match corresponding ones of said plurality of contacts of said semiconductor; and

an attachment device arranged to press said semiconductor against said interconnect structure to provide an electrical connection between said plurality of conductors and said corresponding ones of said plurality of contacts, said attachment device comprising a spring element including a conductive member and a first elastic member comprised of a first elastomeric material having first force transfer characteristics, said first elastic member having a plurality of holes formed therein such that said spring element has overall force transfer characteriştics different from said first force transfer characteristics.

45. The apparatus of claim 44, wherein said spring element further comprises an elastic member comprised of a second elastomeric material having second force transfer characteristics, said second elastic member positioned in at least one of said plurality of holes formed in said first elastic member such that said overall force transfer characteristics are different from said first and second force transfer characteristics.

- 46. The apparatus of claim 44, wherein said spring element further comprises a plurality of second elastic members positioned in a plurality of said plurality of holes in said first elastic member.
- 47. The apparatus of claim 44, wherein said conductive member comprises a plurality of conductive particles.
- **50.** An apparatus for attaching to a plurality of contacts of a semiconductor, said apparatus comprising:

an interconnect structure comprising a plurality of conductors patterned to match corresponding ones of said plurality of contacts of said semiconductor; and

an attachment device arranged to press said semiconductor against said interconnect structure to provide an electrical connection between said plurality of conductors and said corresponding ones of said plurality of contacts, said attachment device comprising a spring element including an elastic member comprised of a conductive member and an elastomeric material having first force transfer characteristics, said first elastic member having at least one hole formed therein such that said spring element has overall force transfer characteristics different from said first force transfer characteristics, said elastic member being shaped so as to engage an outer edge of said semiconductor such that a force applied by said attachment device as said semiconductor is pressed by said attachment device against said interconnect structure is substantially uniform around said semiconductor.

51. The apparatus of claim 50, whe ein said conductive member comprises a plurality of conductive particles.



54. (Amended) An apparatus for attaching to a plurality of contacts of a semiconductor, said apparatus comprising:

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an interconnect structure comprising a plurality of conductors patterned to match corresponding ones of said plurality of contacts of said semiconductor; and

an attachment device arranged to press said interconnect structure against said semiconductor to provide an electrical connection between said plurality of conductors and said corresponding ones of said plurality of contacts, said attachment device comprising a spring element including a first conductive member, a first elastic member and a second elastic member, said first elastic member comprising a first elastomeric material having first force transfer characteristics and said second elastic member comprising a second elastomeric material having second force transfer characteristics, said second elastic member being positioned within said first elastic member such that said spring element has overall force transfer characteristics different from said first and second force transfer characteristics.

- 55. The apparatus of claim 54, further comprising a plurality of said second elastic members formed within said first elastic member.
- 56. The apparatus of claim 54, wherein said conductive member comprises a plurality of conductive particles.
- 63. An apparatus for attaching to a plurality of contacts of a semiconductor, said apparatus comprising:

an interconnect structure comprising a plurality of conductors patterned to match corresponding ones of said plurality of contacts of said semiconductor; and

an attachment device arranged to press said semiconductor against said interconnect structure to provide an electrical connection between said plurality of conductors and said corresponding ones of said plurality of contacts, said attachment device comprising a spring element including a conductive member and an elastic member comprised of an elastomer c material having first force transfer characteristics,

said elastic member having at least one cavity formed therein such that said spring element has overall force transfer characteristics different from said first transfer characteristics of said elastomeric material.

- 64. The apparatus of claim 63, wherein said elastic member has a plurality of cavities formed therein.
- 65. The apparatus of claim 63, wherein said conductive member comprises a plurality of conductive particles.
- **68.** (Amended) An apparatus for attaching to a plurality of contacts of a semiconductor, said apparatus comprising:

an interconnect structure comprising a plurality of conductors patterned to match corresponding ones of said plurality of contacts of said semiconductor; and

an attachment device arranged to press said interconnect structure against said semiconductor to provide an electrical connection between said plurality of conductors and said corresponding ones of said plurality of contacts, said attachment device comprising a spring element including a conductive member and an elastic member having a variable spring constant.

- 69. The apparatus of claim 68, wherein said conductive member comprises a plurality of conductive particles.
- 73. (Amended) An apparatus for attaching to a plurality of contacts of a semiconductor, said apparatus comprising:

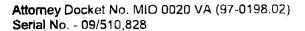
an interconnect structure comprising a plurality of conductors patterned to match corresponding ones of said plurality of contacts of said semiconductor; and

an attachment device arranged to press said semiconductor against said interconnect structure to provide an electrical connection between said plurality of conductors and said corresponding ones of said plurality of contacts, said attachment device comprising a spring element including an elastic member comprised of a first elastomeric material, and a conductive member, wherein said conductive member comprises carbon.

Please add the following new claims:

- 74. (New) The apparatus of claim 44, wherein said conductive member comprises a plurality of conductive particles interspersed within said elastomeric member.
- 75. (New) The apparatus of claim 44, wherein said semiconductor is electrically biased through said spring element.
- **76.** (New) The apparatus of claim 50, wherein said conductive member comprises a plurality of conductive particles interspersed within said elastomeric member.
- 77. (New) The apparatus of claim 50, wherein said semiconductor is electrically biased through said spring element.
- **78.** The apparatus of claim 54, wherein said conductive member comprises a plurality of conductive particles interspersed within said elastomeric member.
- 79. (New) The apparatus of claim 54, wherein said semiconductor is electrically biased through said spring element.
- **80.** (New) The apparatus of claim 63, wherein said conductive member comprises a plurality of conductive particles interspersed within said elastomeric member.

- **81.** (New) The apparatus of claim 63, wherein said semiconductor is electrically biased through said spring element.
- **82.** (New) The apparatus of claim 68, wherein said conductive member comprises a plurality of conductive particles interspersed within said elastomeric member.
- 83. (New) The apparatus of claim 68, wherein said semiconductor is electrically biased through said spring element.
- 84. (New) The apparatus of claim 68, wherein said spring element includes an elastic member having a cross-section defined by at least one peak, wherein said elastic member exhibits a variable spring constant that changes with a degree of compression of said at least one peak.
- **85.** (New) The apparatus of claim 68, wherein said elastic member has a triangular shaped cross-section.
- **86.** (New) The apparatus of claim 68, wherein said elastic member has a repeating triangular shaped cross-section.
- 87. (New) The apparatus of claim 68, wherein said elastic member has a diamond shaped cross-section.
- **88.** (New) The apparatus of claim 68, wherein said elastic member has a repeating diamond shaped cross-section.



REMARKS

KILLWORTH ET AL

Claims 29-31, 36-40, 44-47, 50, 51, 54-56, 63-65, 68, 69, and 73 are pending in the present application. Claims 54, 68, 29, and 73 have been amended, and new claims 74-88 have been added herein.

Rejection Under 35 U.S.C. §102(e)

Claims 29-31 and 36-39 were rejected under 35 U.S.C. §102(e) as being anticipated by U.S. Patent No. 6,046,060 issued April 04, 2000 to Budnaitis et al. (hereinafter "Budnaitis"). According to the M.P.E.P. §706.02, in order to be anticipating under §102, the reference must teach every aspect of the claimed invention. See Carella v. Starlight Archery and Pro Line Co., 804 F.2d 135, 138, 231 U.S.P.Q. 644, 646 (Fed. Cir. 1986).

With regard to independent claim 29 as amended herein, the Applicants believe that the Examiner has not met the burden of establishing a prima facie case of anticipation under 35 USC §102 because Bundaitis fails to teach an attachment device arranged to press the semiconductor between the spring element and the interconnect structure to provide an electrical connection.

As best seen in Figs. 2-4 of Bundaitis, a test device 6 provides test signals carried from the test signal generator 10 to the base unit 7. A selectively conductive elastomer 8 temporarily electrically couples the terminals 13 on the base unit 7 to the pads 20 of the contact sheet 9 (Col. 8, lines 8-15). The contact sheet 9 is further arranged to couple directly to the contacts the semiconductor 1. As such, the test device 6 is not arranged to press the semiconductor between a spring element and an interconnect structure as claimed herein.

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Budnaitis fails to teach every limitation of claim 29. Accordingly, the applicants request the Examiner withdraw the above rejection of claim 29, and the claims that depend therefrom including claims 30-31 and 36-39.

35 U.S.C. §103(a)

Claim 40 was rejected under 35 U.S.C. §103(a) as being anticipated by Budnaitis in view of U.S. Patent No. 6,229,320 issued to Haseyama et al. (hereinafter "Haseyama").

According to the MPEP §706.02(j), in order to establish a *prime facie* case of obviousness, the prior art reference must teach or suggest all the claim limitations.

With regard to independent claim 40 as amended herein via the amendment to base claim 29, the Applicants believe that the Examiner has not met the burden of establishing a prima facie case of obviousness under 35 USC §103 because Budnaitis combined with Haseyama fails to teach an attachment device arranged to press the semiconductor between the spring element and the interconnect structure to provide an electrical connection where the spring element comprises an elastomeric material and a conductor.

As pointed out above, Budnaitis does not teach all of the limitations of claim 29, and thus does not teach all of the limitations of claim 40 as claim 40 depends from claim 29. Haseyama does not teach the use of an elastomeric spring at all. Rather, a "spring action" is achieved in Haseyama using metal contact pins 30. See for example, Col. 6, lines 43-48. See also, Figs. 23A-23D. As pointed out at Col. 16, lines 13-17, the contact pins 30 have an arcuate part 66 to provide the "spring action".

Budnaitis combined with Haseyama fails to teach every limitation of claim 40 thus the Applicants request the Examiner withdraw the above rejection.

Allowable Subject Matter

KILLWORTH ET AL

With regard to the objection to Claim 73, the applicants have rewritten the claim in independent form including all of the limitations of the base claim 29 per the Examiner's suggestion. As such, the applicants request the Examiner withdraw the objection.

With regard to the new claims added herein, each of the added claims is dependent upon a base claim that has already been determined allowable.

The applicants thank the Examiner for the early indication of allowable subject matter.

CONCLUSION

For all of the above reasons, the applicants respectfully submit that the above claims represent allowable subject matter. The Examiner is encouraged to contact the undersigned to resolve efficiently any formal matters or to discuss any aspects of the application or of this response. Otherwise, early notification of allowable subject matter is respectfully solicited.

Respectfully submitted,

KILLWORTH, GOTTMAN, HAGAN &

SCHAEFF, L.L.P.

By

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